



General Description

The QM3052M6 is the highest performance trench N-ch MOSFETs with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The QM3052M6 meet the RoHS and Green Product requirement , 100% EAS guaranteed with full function reliability approved.

Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|-------------------------|--|------------|-------|
| V_{DS} | Drain-Source Voltage | 30 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| $I_D @ T_C=25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^{1,7}$ | 62 | A |
| $I_D @ T_C=100^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 40 | A |
| $I_D @ T_A=25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 13.1 | A |
| $I_D @ T_A=70^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V^1$ | 10.5 | A |
| I_{DM} | Pulsed Drain Current ² | 150 | A |
| EAS | Single Pulse Avalanche Energy ³ | 69 | mJ |
| I_{AS} | Avalanche Current | 37 | A |
| $P_D @ T_C=25^\circ C$ | Total Power Dissipation ⁴ | 46.3 | W |
| $P_D @ T_A=25^\circ C$ | Total Power Dissipation ⁴ | 2 | W |
| T_{STG} | Storage Temperature Range | -55 to 150 | °C |
| T_J | Operating Junction Temperature Range | -55 to 150 | °C |

Product Summary

| BVDSS | RDS(on) | ID |
|-------|---------|-----|
| 30V | 8.0 mΩ | 62A |

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

PRPAK5X6 Pin Configuration



Thermal Data

| Symbol | Parameter | Typ. | Max. | Unit |
|-----------------|--|------|------|------|
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient ¹ | --- | 62 | °C/W |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case ¹ | --- | 2.7 | °C/W |

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|-------------------------------------|--|--|------|------|------|-------|
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _D =250μA | 30 | --- | --- | V |
| △BV _{DSS} /△T _J | BVDSS Temperature Coefficient | Reference to 25°C, I _D =1mA | --- | 0.01 | --- | V/°C |
| R _{DS(ON)} | Static Drain-Source On-Resistance ² | V _{GS} =10V, I _D =30A | --- | 6.4 | 8.0 | mΩ |
| | | V _{GS} =4.5V, I _D =15A | --- | 10 | 12.5 | |
| V _{GS(th)} | Gate Threshold Voltage | V _{GS} =V _{DS} , I _D =250μA | 1.2 | 1.5 | 2.5 | V |
| △V _{GS(th)} | V _{GS(th)} Temperature Coefficient | | --- | -3.1 | --- | mV/°C |
| I _{DSS} | Drain-Source Leakage Current | V _{DS} =24V, V _{GS} =0V, T _J =25°C | --- | --- | 1 | uA |
| | | V _{DS} =24V, V _{GS} =0V, T _J =55°C | --- | --- | 5 | |
| I _{GSS} | Gate-Source Leakage Current | V _{GS} =±20V, V _{DS} =0V | --- | --- | ±100 | nA |
| g _{fs} | Forward Transconductance | V _{DS} =5V, I _D =30A | --- | 41 | --- | S |
| R _g | Gate Resistance | V _{DS} =0V, V _{GS} =0V, f=1MHz | --- | 3.9 | 5.8 | Ω |
| Q _g | Total Gate Charge (4.5V) | V _{DS} =15V, V _{GS} =4.5V, I _D =15A | --- | 7.4 | 10.4 | nC |
| Q _{gs} | Gate-Source Charge | | --- | 3.0 | 4.2 | |
| Q _{gd} | Gate-Drain Charge | | --- | 2.2 | 3.1 | |
| T _{d(on)} | Turn-On Delay Time | V _{DD} =15V, V _{GS} =10V, R _G =3.3Ω | --- | 4.5 | 9 | ns |
| T _r | Rise Time | | --- | 22 | 40 | |
| T _{d(off)} | Turn-Off Delay Time | | --- | 26 | 52 | |
| T _f | Fall Time | | --- | 19 | 38 | |
| C _{iss} | Input Capacitance | V _{DS} =15V, V _{GS} =0V, f=1MHz | --- | 710 | 994 | pF |
| C _{oss} | Output Capacitance | | --- | 210 | 294 | |
| C _{rss} | Reverse Transfer Capacitance | | --- | 98 | 137 | |

Guaranteed Avalanche Characteristics

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|--------|--|---|------|------|------|------|
| EAS | Single Pulse Avalanche Energy ⁵ | V _{DD} =25V, L=0.1mH, I _{AS} =30A | 45 | --- | --- | mJ |

Diode Characteristics

| Symbol | Parameter | Conditions | Min. | Typ. | Max. | Unit |
|-----------------|--|---|------|------|------|------|
| I _S | Continuous Source Current ^{1,6} | V _G =V _D =0V, Force Current | --- | --- | 62 | A |
| I _{SM} | Pulsed Source Current ^{2,6} | | --- | --- | 150 | A |
| V _{SD} | Diode Forward Voltage ² | V _{GS} =0V, I _S =1A, T _J =25°C | --- | --- | 1 | V |

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD}=25V,V_{GS}=10V,L=0.1mH,I_{AS}=37A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The Min. value is 100% EAS tested guarantee.
- 6.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.
- 7.Package limitation current is 85A.

Typical Characteristics

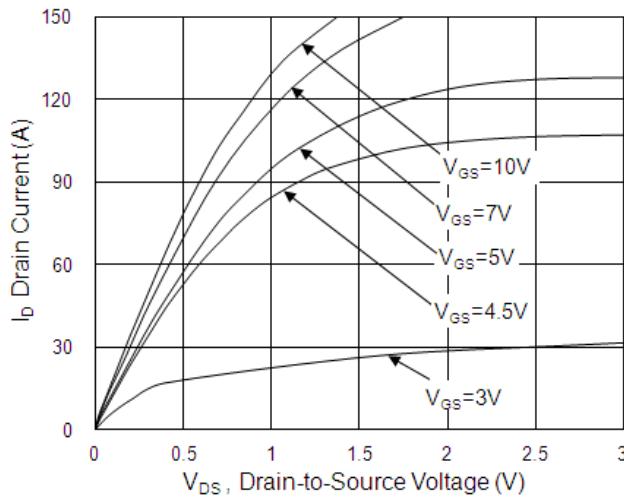


Fig.1 Typical Output Characteristics

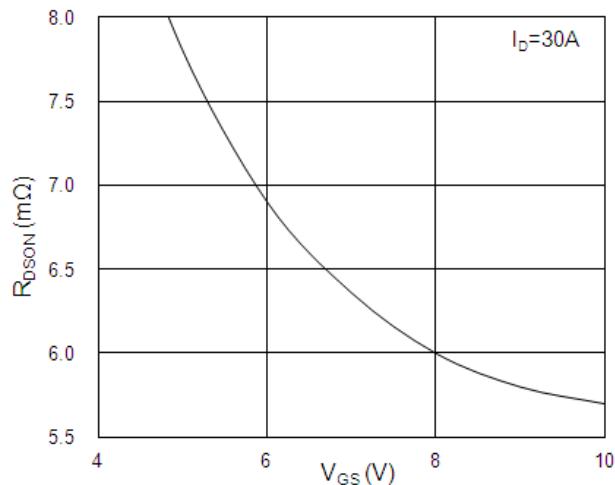


Fig.2 On-Resistance vs. Gate-Source

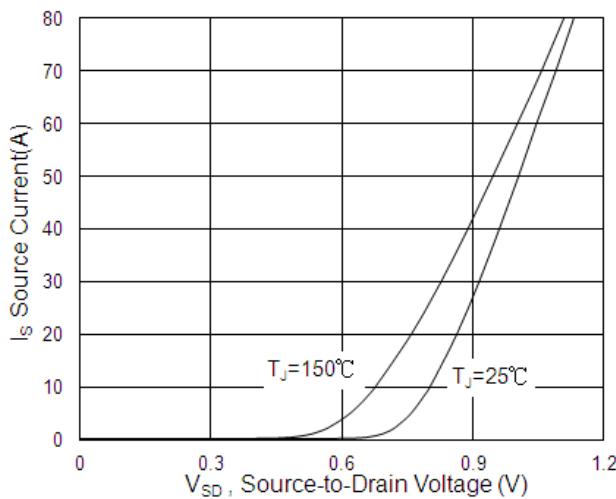


Fig.3 Forward Characteristics of Reverse

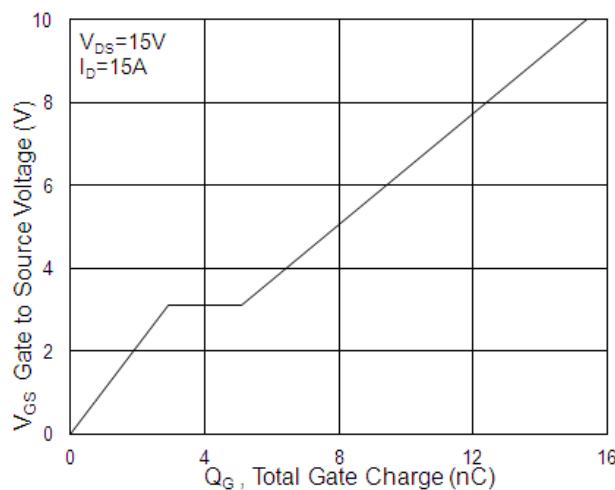


Fig.4 Gate-Charge Characteristics

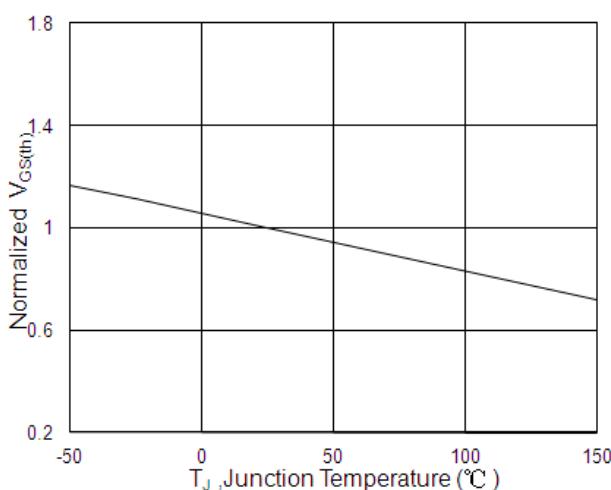


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

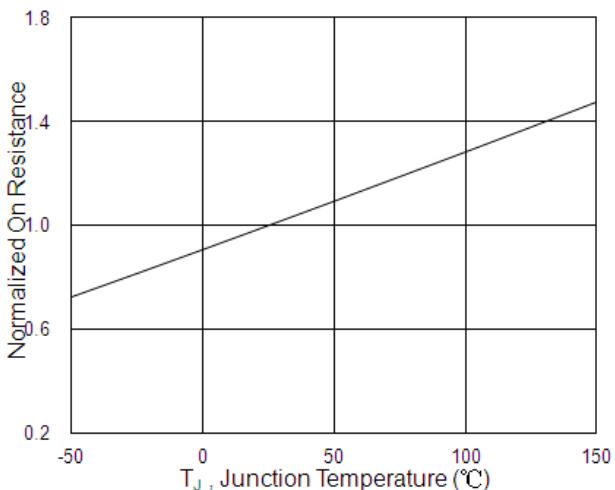
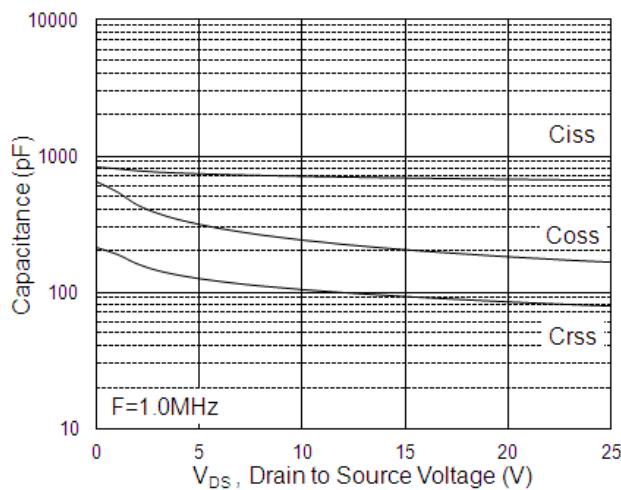
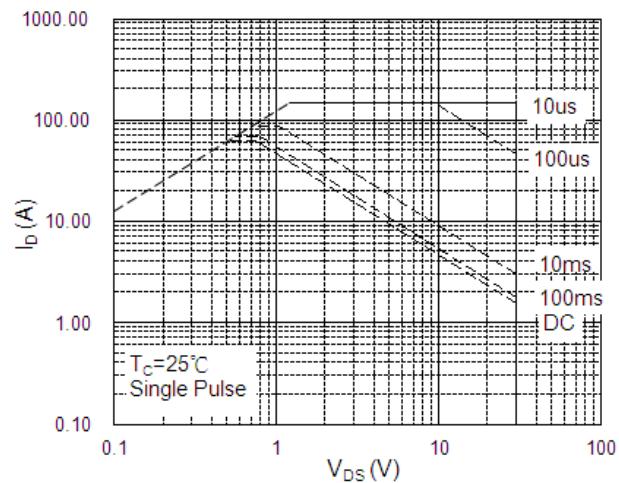
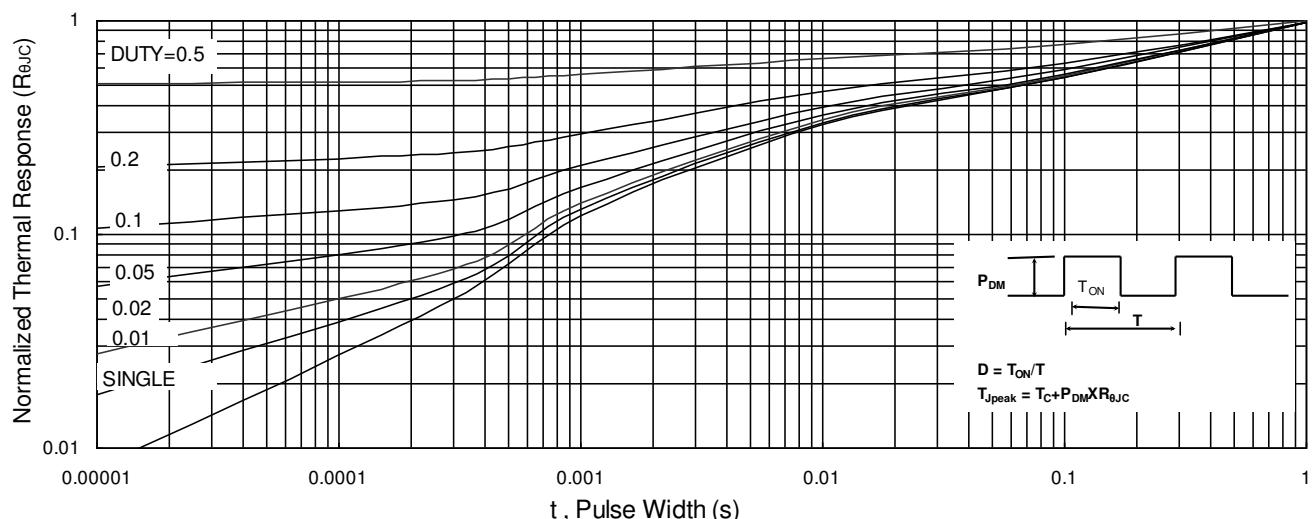
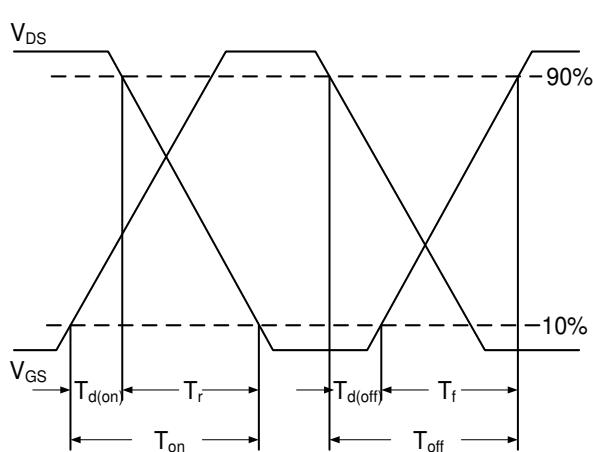
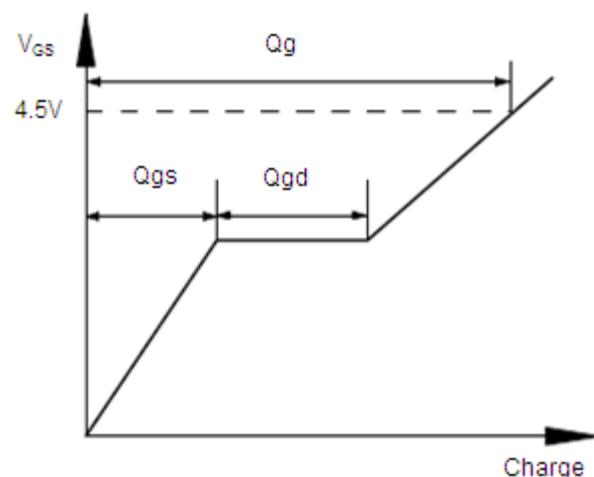
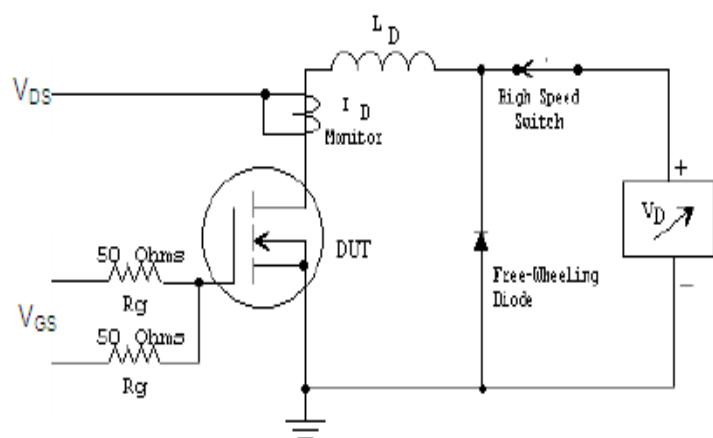


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

N-Ch 30V Fast Switching MOSFETs

Fig.7 Capacitance

Fig.8 Safe Operating Area

Fig.9 Normalized Maximum Transient Thermal Impedance

Fig.10 Switching Time Waveform

Fig.11 Gate Charge Waveform

N-Ch 30V Fast Switching MOSFETs


$$EAS = \frac{1}{2} L \times I_{AS}^2$$

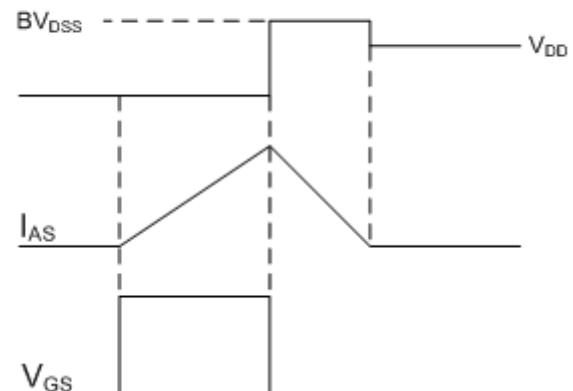


Fig.12 Unclamped Inductive Switching Test Circuit & Waveforms